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Titolo	Graph Embedding for Pattern Analysis [[electronic resource] /] / edited by Yun Fu, Yunqian Ma
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ISBN	1-283-91069-1 1-4614-4457-8
Edizione	[1st ed. 2013.]
Descrizione fisica	1 online resource (263 p.)
Disciplina	006.4
Soggetti	Electrical engineering Pattern recognition Artificial intelligence Signal processing Image processing Speech processing systems Communications Engineering, Networks Pattern Recognition Artificial Intelligence Signal, Image and Speech Processing
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references.
Nota di contenuto	Multilevel Analysis of Attributed Graphs for Explicit Graph Embedding in Vector Spaces -- Feature Grouping and Selection over an Undirected Graph -- Median Graph Computation by Means of Graph Embedding into Vector Spaces -- Patch Alignment for Graph Embedding -- Feature Subspace Transformations for Enhancing K-Means Clustering -- Learning with 1-Graph for High Dimensional Data Analysis -- Graph-Embedding Discriminant Analysis on Riemannian Manifolds for Visual Recognition -- A Flexible and Effective Linearization Method for Subspace Learning -- A Multi-Graph Spectral Approach for Mining Multi-Source Anomalies -- Graph Embedding for Speaker Recognition.
Sommario/riassunto	Graph Embedding for Pattern Analysis covers theory methods, computation, and applications widely used in statistics, machine

learning, image processing, and computer vision. This book presents the latest advances in graph embedding theories, such as nonlinear manifold graph, linearization method, graph based subspace analysis, L1 graph, hypergraph, undirected graph, and graph in vector spaces. Real-world applications of these theories are spanned broadly in dimensionality reduction, subspace learning, manifold learning, clustering, classification, and feature selection. A selective group of experts contribute to different chapters of this book which provides a comprehensive perspective of this field.

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